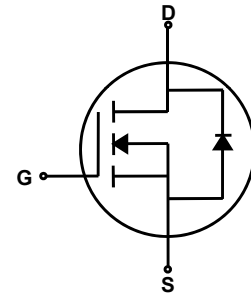
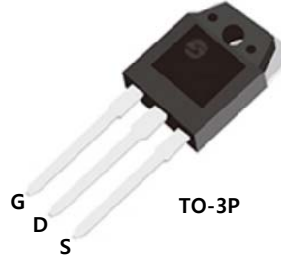
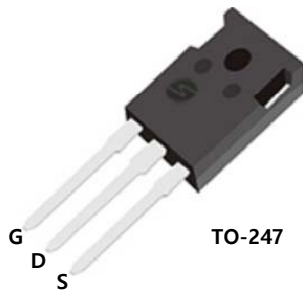


**General Description**

This Power MOSFET is produced using Maple semi's Advanced Super-Junction technology. This advanced technology has been especially tailored to minimize conduction loss, provide superior switching performance, and withstand high energy pulse in the avalanche and commutation mode. These devices are well suited for AC/DC power conversion in switching mode operation for higher efficiency.

**Features**

- 42A, 600V,  $R_{DS(on)typ} = 70\text{ m}\Omega @ V_{GS} = 10\text{ V}$
- Low gate charge ( typical 90.3nC)
- High ruggedness
- Fast switching
- Intrinsic Fast-Recovery Body Diode
- 100% avalanche tested
- Improved dv/dt capability



**Absolute Maximum Ratings**

$T_C = 25^\circ\text{C}$  unless otherwise noted

Symbol	Parameter	SLH60R080SSD	SLW60R080SSD	Units
$V_{DSS}$	Drain-Source Voltage	600		V
$I_D$	Drain Current - Continuous ( $T_C = 25^\circ\text{C}$ ) - Continuous ( $T_C = 100^\circ\text{C}$ )	42		A
		18.7		A
$I_{DM}$	Drain Current - Pulsed (Note 1)	126		A
$V_{GSS}$	Gate-Source Voltage	$\pm 30$		V
EAS	Single Pulsed Avalanche Energy (Note 2)	550		mJ
$I_{AR}$	Avalanche Current (Note 1)	4.5		A
dv/dt	Peak Diode Recovery dv/dt (Note 3)	50		V/ns
$P_D$	Power Dissipation ( $T_C = 25^\circ\text{C}$ ) - Derate above $25^\circ\text{C}$	295		W
		2.46		W/ $^\circ\text{C}$
$T_J, T_{STG}$	Operating and Storage Temperature Range	-55 to +150		$^\circ\text{C}$
$T_L$	Maximum lead temperature for soldering purposes, 1/8" from case for 5 seconds	300		$^\circ\text{C}$

\* Drain current limited by maximum junction temperature.

**Thermal Characteristics**

Symbol	Parameter	SLH60R080SSD	SLW60R080SSD	Units
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case	0.41		$^\circ\text{C}/\text{W}$
$R_{\theta JS}$	Thermal Resistance, Case-to-Sink Typ.	--		$^\circ\text{C}/\text{W}$
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient	50.0		$^\circ\text{C}/\text{W}$

**Electrical Characteristics** $T_C = 25^\circ\text{C}$  unless otherwise noted

Symbol	Parameter	Test Conditions	Min	Typ	Max	Units
<b>Off Characteristics</b>						
$BV_{DSS}$	Drain-Source Breakdown Voltage	$V_{GS} = 0\text{ V}, I_D = 250\text{ }\mu\text{A}$	600	--	--	V
$\Delta BV_{DSS} / \Delta T_J$	Breakdown Voltage Temperature Coefficient	$I_D = 250\text{ }\mu\text{A}$ , Referenced to $25^\circ\text{C}$	--	0.59	--	$\text{V}/^\circ\text{C}$
$I_{DSS}$	Zero Gate Voltage Drain Current	$V_{DS} = 600\text{ V}, V_{GS} = 0\text{ V}$	--	--	10	$\mu\text{A}$
		$V_{DS} = 480\text{ V}, T_C = 125^\circ\text{C}$	--	--	10	$\mu\text{A}$
$I_{GSSF}$	Gate-Body Leakage Current, Forward	$V_{GS} = 30\text{ V}, V_{DS} = 0\text{ V}$	--	--	100	nA
$I_{GSSR}$	Gate-Body Leakage Current, Reverse	$V_{GS} = -30\text{ V}, V_{DS} = 0\text{ V}$	--	--	-100	nA

**On Characteristics**

$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_D = 800\text{ }\mu\text{A}$	3.0	4.0	5.0	V
$R_{DS(on)}$	Static Drain-Source On-Resistance	$V_{GS} = 10\text{ V}, I_D = 21\text{ A}$	--	70	80	$\text{m}\Omega$
$R_g$	Gate resistance	$F=1\text{MHz}$	--	0.7	--	$\Omega$

**Dynamic Characteristics**

$C_{iss}$	Input Capacitance	$V_{DS} = 50\text{ V}, V_{GS} = 0\text{ V},$ $f = 1.0\text{ MHz}$	--	3300	--	pF
$C_{oss}$	Output Capacitance		--	136	--	pF
$C_{rss}$	Reverse Transfer Capacitance		--	2.3	--	pF

**Switching Characteristics**

$t_{d(on)}$	Turn-On Delay Time	$V_{DD} = 400\text{ V}, I_D = 21\text{ A},$ $R_G = 1.8\text{ }\Omega, V_{GS} = 10\text{ V}$ (Note 4, 5)	--	24	--	ns
$t_r$	Turn-On Rise Time		--	38	--	ns
$t_{d(off)}$	Turn-Off Delay Time		--	48	--	ns
$t_f$	Turn-Off Fall Time		--	10	--	ns
$Q_g$	Total Gate Charge		$V_{DS} = 480\text{ V}, I_D = 21\text{ A},$ $V_{GS} = 10\text{ V}$ (Note 4, 5)	--	90.3	--
$Q_{gs}$	Gate-Source Charge		--	22.9	--	nC
$Q_{gd}$	Gate-Drain Charge		--	45.6	--	nC

**Drain-Source Diode Characteristics and Maximum Ratings**

$I_S$	Maximum Continuous Drain-Source Diode Forward Current		--	42	--	A
$V_{SD}$	Drain-Source Diode Forward Voltage	$V_{GS} = 0\text{ V}, I_S = 21\text{ A}$	--	0.9	1.1	V
$t_{rr}$	Reverse Recovery Time	$V_{GS} = 50\text{ V}, I_S = 21\text{ A},$	--	158	--	ns
$Q_{rr}$	Reverse Recovery Charge	$di_F / dt = 100\text{ A}/\mu\text{s}$ (Note 4)	--	0.95	--	$\mu\text{C}$

**Notes:**

1. Repetitive Rating : Pulse width limited by maximum junction temperature
2.  $L = 54\text{ mH}, I_{AS} = 4.5\text{ A}, V_{DD} = 60\text{ V}, R_G = 25\Omega$ , Starting  $T_J = 25^\circ\text{C}$
3.  $I_{SD} \leq 20\text{ A}, di/dt \leq 100\text{ A}/\mu\text{s}, V_{DD} \leq BV_{DSS}$ , Starting  $T_J = 25^\circ\text{C}$
4. Pulse Test : Pulse width  $\leq 300\mu\text{s}$ , Duty cycle  $\leq 2\%$
5. Essentially independent of operating temperature

Typical Characteristics

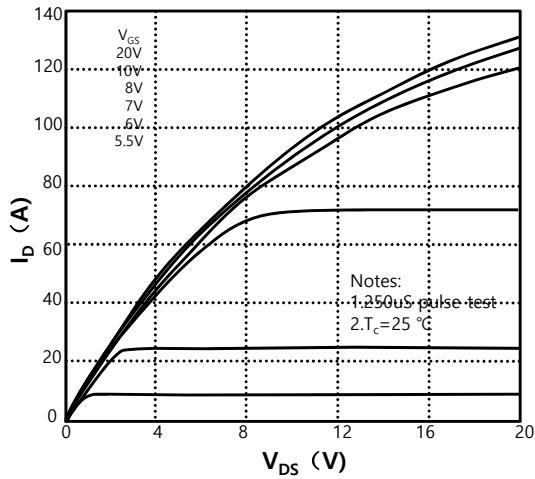


Figure 1. On-Region Characteristics

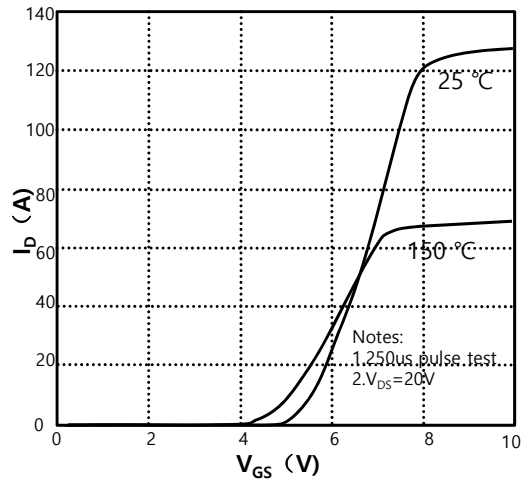


Figure 2. Transfer Characteristics

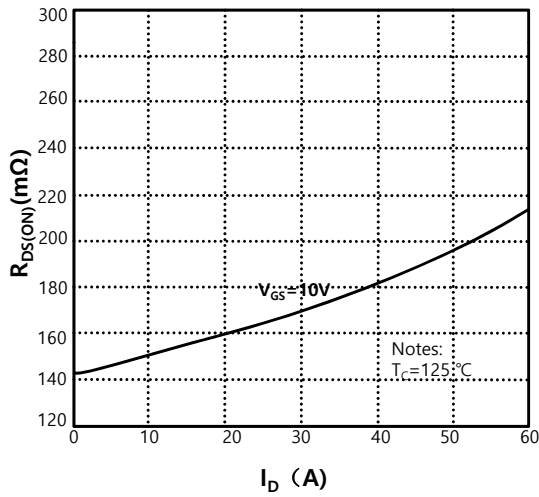


Figure 3. On-Resistance Variation vs Drain Current and Gate Voltage

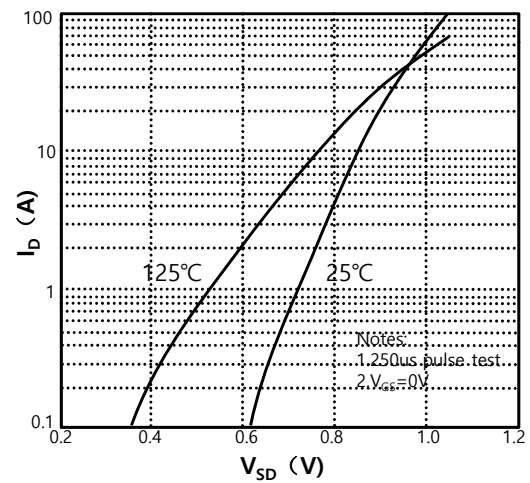


Figure 4. Body Diode Forward Voltage Variation with Source Current and Temperature

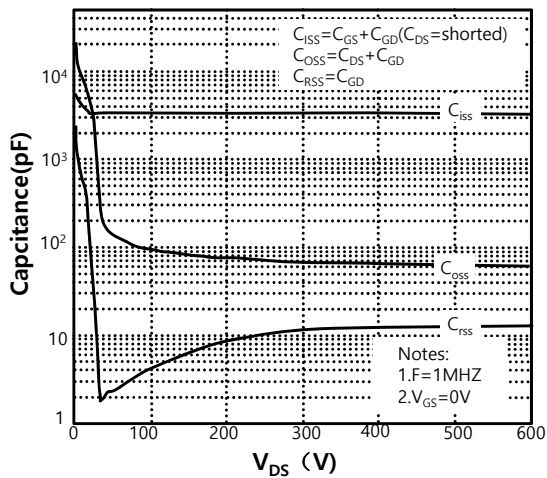


Figure 5. Capacitance Characteristics

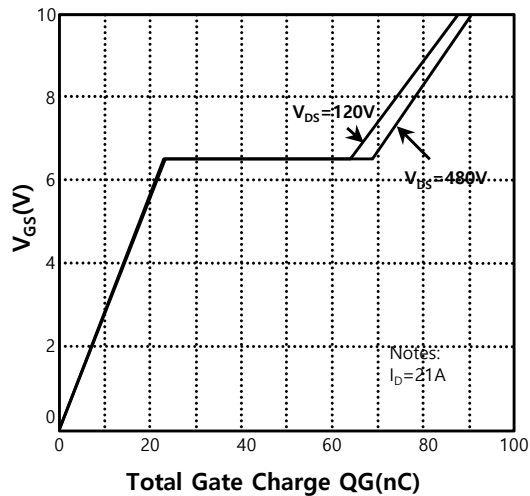


Figure 6. Gate Charge Characteristics

Typical Characteristics (Continued)

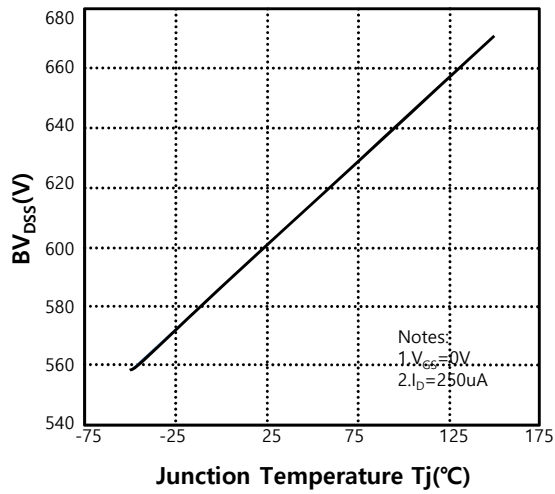


Figure 7. Breakdown Voltage Variation vs Temperature

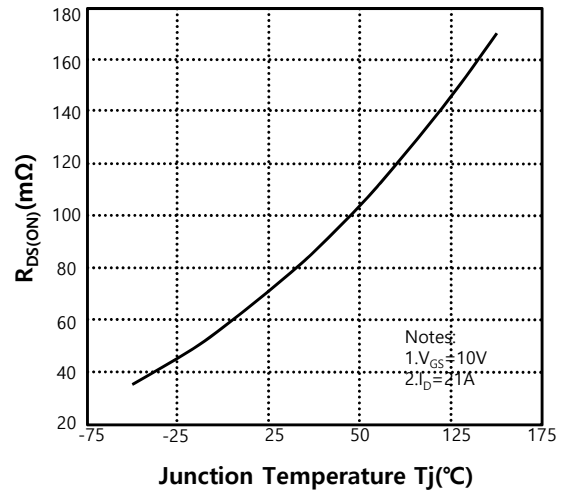


Figure 8. On-Resistance Variation vs Temperature

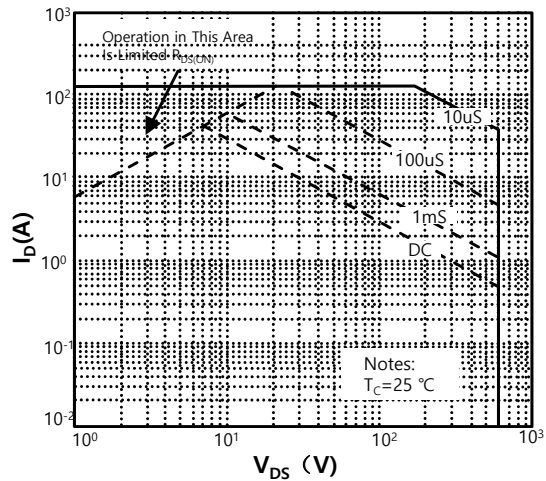


Figure 9-1. Maximum Safe Operating Area

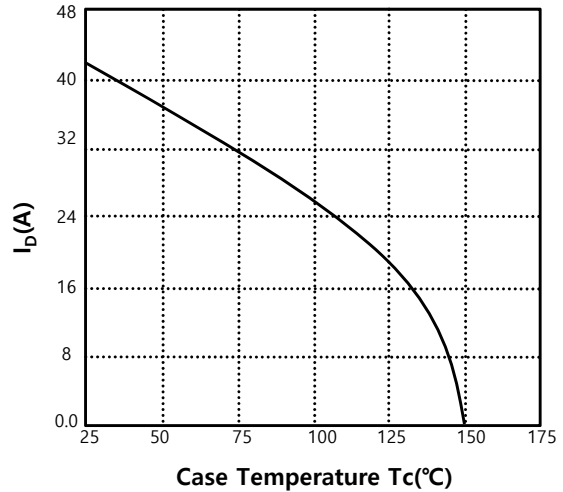
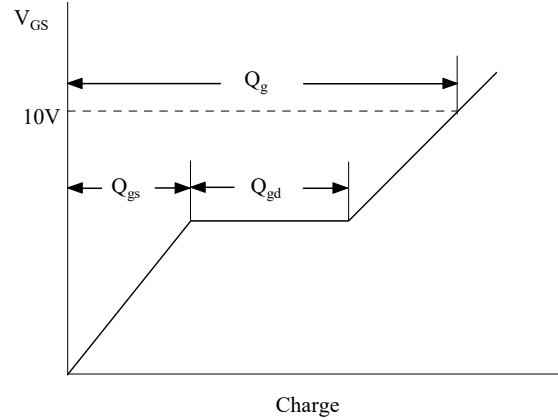
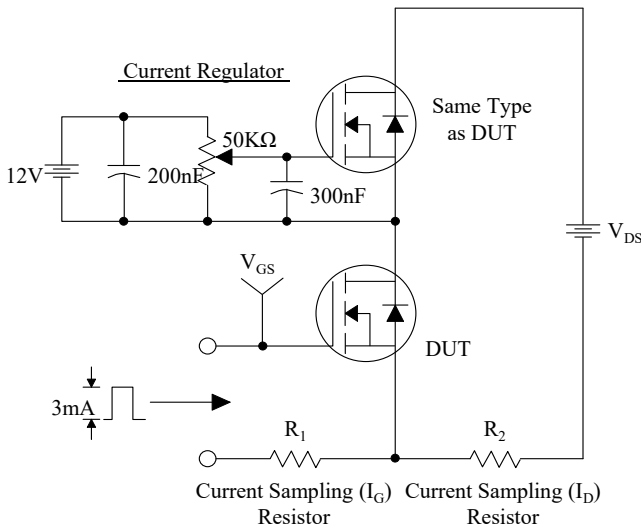
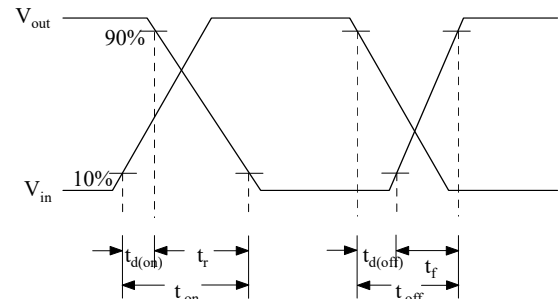
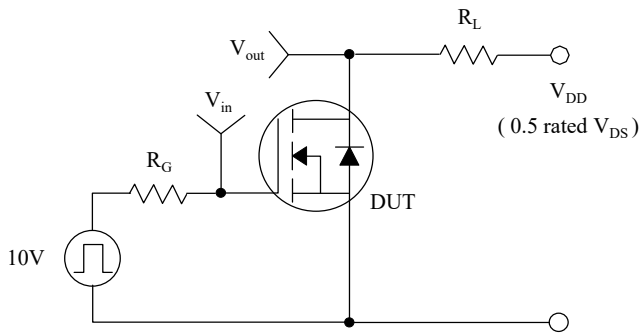


Figure 10. Maximum Drain Current vs Case Temperature

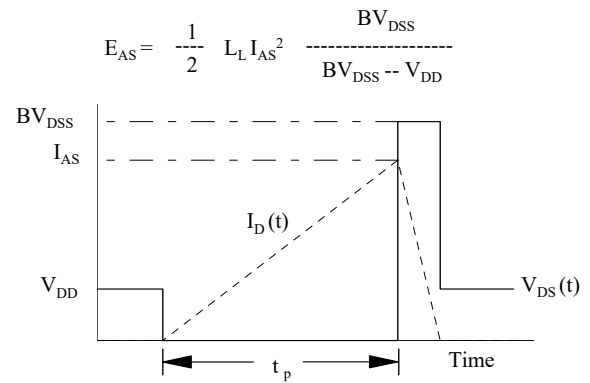
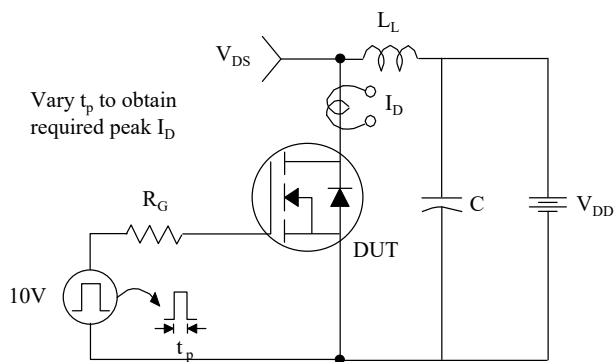
### Gate Charge Test Circuit & Waveform



### Resistive Switching Test Circuit & Waveforms



### Unclamped Inductive Switching Test Circuit & Waveforms



### Peak Diode Recovery dv/dt Test Circuit & Waveforms

